



Continuation of Substance of Interview including description of the general nature of what was discussed: Examiner contacted applicant's representative, Takashi Saito, on December 29, 2009 to discuss further clarifying that the second silicon layer is in physical contact with the first semiconductor layer in order to distinguish the claimed device from the device shown in Yoshiko. On January 6, 2010, applicant's representative gave permission for the clarification to be made in an Examiner's Amendment. On January 7, 2010, Examiner contacted applicant's representative to get permission to clarify which claim 15 depends from. Clarification was provided and the proper dependency will be detailed in the Examiner's Amendment..